Notice of References Cited	Application/Control No. 10/574,219	Applicant(s)/Patent Under Reexamination SCHULZ ET AL.		
Notice of References offed	Examiner	Art Unit	Page 1 of 1	
	LUKE E. KARPINSKI	1616		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,042,816 A	03-2000	Shen, Yan-Fei	424/65
*	В	US-2002/0077372 A1	06-2002	GERS-BARLAG et al.	516/98
*	С	US-2005/0265940 A1	12-2005	Okada, Toru	424/066
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-I ATENT DOCUMENTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	w				
	х				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.